## Application/Control No. Applicant(s)/Patent Under Reexamination 10/613,495 CHEN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1774 Pamela R. Schwartz **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,780,924 08-2004 524/555 Shih et al. В US-2001/0004487 06-2001 Kaneko et al. 428/195 С US-2003/0186003 10-2003 Nakano et al. 428/32.1 US-D US-E F US-US-G US-Н US-1 US-J US-Κ US-US-Μ FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν O Ρ Q R s

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